

Embedded test processors (ETP)

Petersen, Kim; Magnhagen, Bengt; Linden, Henric BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 89-92: ill

MCM-test

Magnhagen, Bengt; Linden, Henric BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 297-304: ill

Test strategy for a 486 computer multichip module

Magnhagen, Bengt BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 339-340: ill